The SID4-SWIR wavefront sensor integrates Phasics patented technology with an InGaAs detector. Thanks to its high spatial resolution and great sensitivity, it offers accurate wavefront measurement over its whole spectral range from 900 nm to 1.7μm.

The SID4-SWIR is an innovative solution for testing SWIR lens used in optical communications, inspection instruments or night vision in military and surveillance devices. It provides both MTF and aberrations at once. The SID4-SWIR also enables characterizing SWIR sources like 1.55μm lasers or LEDs for laser guiding systems.

**KEY FEATURES**
- Extended spectral range from 0.9 to 1.7μm
- High resolution – 80 X 64
- High sensitivity - <2nm phase noise through the whole spectral range (compatible with low energy IR source)
- High stability
- Cooled detector
- Compact & Cost effective

**SPECIFICATIONS**
- Wavelength range: 0.9 – 1.7μm
- Aperture dimensions: 9.60 x 7.68 mm²
- Spatial resolution: 120 μm
- Phase and intensity Sampling: 80 X 64
- Accuracy: 15 nm RMS
- Resolution (Phase): <2nm RMS
- Acquisition rate: 120 fps
- Real-time processing frequency: > 7 fps (full resolution)
- Interface: Giga Ethernet
- Dimensions: 100 x 55 x 63 mm
- Weight: 455 g

**PHASICS** - The phase control company